

<b>Notice of References Cited</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination	
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	Examiner	Art Unit	Page 1 of 1
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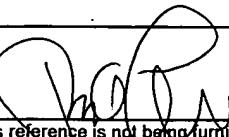
**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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	U	JP 2000-290431 (abstract and translation in English)
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	X	 

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